

IN THE CLAIMS

Please amend the claims as follows:

1.-8. (Cancelled)

9. (Previously Presented) The method of Claim 21, wherein the step of classifying is performed by a table lookup, the table having been prepared based upon benchmark results.

10. (Cancelled)

11. (Previously Presented) The method of Claim 22, wherein at least one defective floating point unit of the plurality of floating point execution units is marked disabled and at least one remaining floating point unit of the plurality of floating point execution units is marked enabled.

12. (Previously Presented) The method of Claim 21, wherein a functional unit of the plurality of functional units is a branch prediction unit, and wherein the branch prediction unit is capable of being disabled through programming the resource status bits.

13. (Previously Presented) The method of Claim 12, wherein at least one defective floating point unit of a plurality of floating point execution units on the partially defective processor integrated circuit is marked disabled and at least one remaining floating point unit of the plurality of floating point execution units is marked enabled.

14.-18. (Cancelled)

19. (Previously Presented) The method of Claim 11, wherein the resource status register is implemented in a programmable read-only memory, and wherein the programmable read-only memory is programmed prior to sale.

20. (Previously Presented) The method of Claim 12, wherein the resource status register is implemented in a programmable read-only memory, and wherein the programmable read-only memory is programmed prior to sale.

21. (Currently Amended) A method of selling a partially defective processor integrated circuit comprising the steps of:

providing a plurality of functional units on the integrated circuit, the functional units of functional unit types selected from the group of functional unit types consisting of integer execution units, floating point execution units, branch prediction units, address operation units, and load/store units;

providing a resource status register wherein functional units of the plurality of functional units may be marked with status selected from the group consisting of enabled and disabled;

testing the integrated circuit to determine which functional units are defective;

programming the resource status register to mark defective functional units as disabled and remaining functional units as enabled;

classifying the integrated circuit into bins according to performance available with the enabled functional units;

packaging the integrated circuit; and

selling the integrated circuit as capable of performance appropriate for the bin into which it was classified;

wherein a functional unit of a functional unit type selected from the group of functional unit types consisting of floating point units, integer operation units, load/store units, and address operation units; may only be marked disabled and the integrated circuit sold if there is at least one remaining non-defective functional unit of the same functional unit type marked enabled.

22. (Previously Presented) The method of claim 21 wherein the functional units are of functional unit types selected from the group of functional unit types consisting of a functional unit type selected from the group of functional unit types consisting of floating point units, integer operation units, load/store units, and address operation units.

23-24. (Cancelled)

25. (New) A method of selling a partially defective processor integrated circuit comprising the steps of:

providing a plurality of functional units on the integrated circuit;

providing a resource status bit associated with each functional unit wherein each functional unit of the plurality of functional units may be marked with status selected from the group consisting of enabled and disabled;

testing an integrated circuit to determine which functional units are defective;

programming the resource status register to mark defective functional units as disabled and remaining functional units as enabled;

determining a remaining performance by lookup in a performance table to classify the integrated circuit into bins according to performance available with the enabled functional units, the performance table having been prepared based upon benchmark results;

packaging the integrated circuit; and

selling the integrated circuit as capable of performance appropriate for the bin into which it was classified;

wherein the partially defective processor integrated circuit further comprises an instruction decode and dispatch unit, at least one functional unit of the plurality of functional units drives a reject line coupled to the instruction decode and dispatch unit, and wherein when the instruction decode and dispatch unit dispatches an instruction to the at least one functional unit and the functional unit activates the reject line, the instruction decode and dispatch unit re-dispatches the instruction to another functional unit of the plurality of functional units.